

Application/Control No.	Applicant(s)/Patent under Reexamination
10/621,371	SHIUE ET AL.
Examiner	Art Unit
Jeffrey R. Snay	1743

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Class	Subclass	Date	Examiner
436	164 166 172 92 96 63 86 808 810 811	6/20/2005	JRS
422	61	6/20/2005	JRS

INI	ERFERENC	ERENCE SEARCHED		
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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